DATA SHEET



MOS FIELD EFFECT TRANSISTOR NP36P06KDG

SWITCHING **P-CHANNEL POWER MOSFET**

DESCRIPTION

The NP36P06KDG is P-channel MOS Field Effect Transistor designed for high current switching applications.

ORDERING INFORMATION

PART NUMBER	LEAD PLATING	PACKING	PACKAGE	
NP36P06KDG-E1-AY Note		Tape 800 p/reel	TO 000 (MD 0571/)	
NP36P06KDG-E2-AY Note	P06KDG-E2-AY Note Pure Sn (Tin)		TO-263 (MP-25ZK)	

Note Pb-free (This product does not contain Pb in external electrode.)

FEATURES

• Super low on-state resistance

 $R_{DS(on)1} = 29.5 \text{ m}\Omega \text{ MAX}. \text{ (V}_{GS} = -10 \text{ V}, I_{D} = -18 \text{ A})$

 $R_{DS(on)2} = 37.5 \text{ m}\Omega \text{ MAX.} \text{ (Vgs} = -4.5 \text{ V, Ip} = -18 \text{ A)}$

Low input capacitance

Ciss = 3100 pF TYP.

(TO-263)



ABSOLUTE MAXIMUM RATINGS (TA = 25°C)

Drain to Source Voltage (VGS = 0 V)	VDSS	-60	V
Gate to Source Voltage (VDS = 0 V)	Vgss	∓20	V
Drain Current (DC) (Tc = 25°C)	I _{D(DC)}	∓36	Α
Drain Current (pulse) Note1	I _{D(pulse)}	∓108	Α
Total Power Dissipation (Tc = 25°C)	P _{T1}	56	W
Total Power Dissipation (T _A = 25°C)	P _{T2}	1.8	W
Channel Temperature	Tch	175	°C
Storage Temperature	T _{stg}	-55 to +175	°C
Single Avalanche Current Note2	las	23	Α
Single Avalanche Energy Note2	Eas	54	mJ

Notes 1. PW \leq 10 μ s, Duty Cycle \leq 1%

2. Starting T_{ch} = 25°C, V_{DD} = -30 V, R_G = 25 Ω , V_{GS} = -20 \rightarrow 0 V

THERMAL RESISTANCE

Channel to Case Thermal Resistance	Rth(ch-C)	2.68	°C/W
Channel to Ambient Thermal Resistance	Rth(ch-A)	83.3	°C/W

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ELECTRICAL CHARACTERISTICS (TA = 25°C)

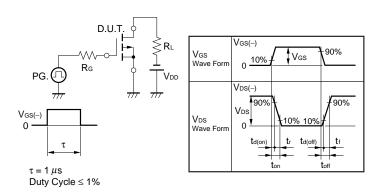
CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Zero Gate Voltage Drain Current	IDSS	V _{DS} = -60 V, V _{GS} = 0 V			-10	μΑ
Gate Leakage Current	Igss	V _{GS} = ∓20 V, V _{DS} = 0 V			∓100	nA
Gate to Source Threshold Voltage	V _{GS(th)}	V _{DS} = -10 V, I _D = -1 mA	-1.0	-1.6	-2.5	V
Forward Transfer Admittance Note	y _{fs}	V _{DS} = -10 V, I _D = -18 A	12	23		S
Drain to Source On-state Resistance Note	RDS(on)1	V _{GS} = -10 V, I _D = -18 A		23.1	29.5	mΩ
	R _{DS(on)2}	V _{GS} = -4.5 V, I _D = -18 A		27.0	37.5	mΩ
Input Capacitance	Ciss	V _{DS} = -10 V,		3100		pF
Output Capacitance	Coss	V _{GS} = 0 V,		350		pF
Reverse Transfer Capacitance	Crss	f = 1 MHz		205		pF
Turn-on Delay Time	t _{d(on)}	V _{DD} = -30 V, I _D = -18 A,		8		ns
Rise Time	tr	V _{GS} = -10 V,		11		ns
Turn-off Delay Time	td(off)	R _G = 0 Ω		210		ns
Fall Time	tf			110		ns
Total Gate Charge	Q _G	V _{DD} = -48 V,		54		nC
Gate to Source Charge	Q _{GS}	V _{GS} = -10 V,		7		nC
Gate to Drain Charge	Q _{GD}	I _D = -36 A		15		nC
Body Diode Forward Voltage Note	V _{F(S-D)}	I _F = -36 A, V _{GS} = 0 V		0.98	1.5	V
Reverse Recovery Time	trr	I _F = -36 A, V _{GS} = 0 V,		43		ns
Reverse Recovery Charge	Qrr	di/dt = –100 A/μs		56		nC

Note Pulsed test PW \leq 350 μ s, Duty Cycle \leq 2%

TEST CIRCUIT 1 AVALANCHE CAPABILITY

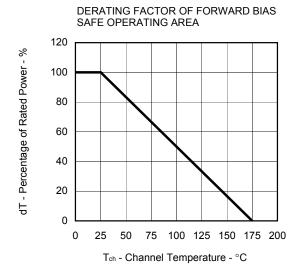
$PG. \square \Rightarrow D.U.T.$ $RG = 25 \Omega \square \Rightarrow VDD$ $V_{DD} \qquad \qquad VDD$

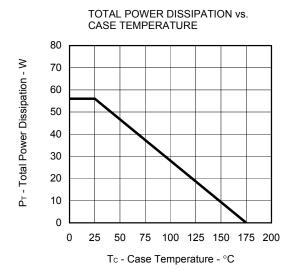
TEST CIRCUIT 2 SWITCHING TIME



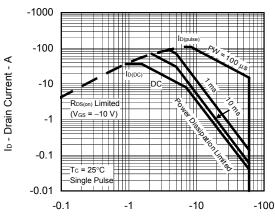
TEST CIRCUIT 3 GATE CHARGE

TYPICAL CHARACTERISTICS (TA = 25°C)



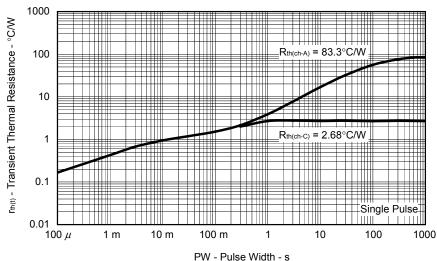


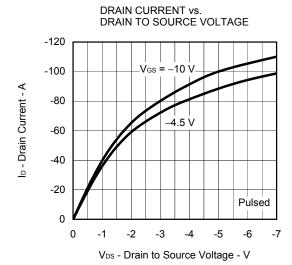
FORWARD BIAS SAFE OPERATING AREA

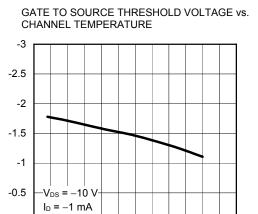


V_{DS} - Drain to Source Voltage - V

TRANSIENT THERMAL RESISTANCE vs. PULSE WIDTH







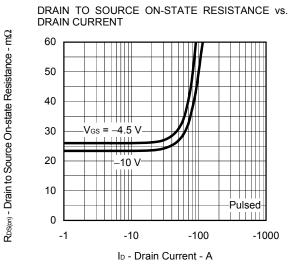
75

Tch - Channel Temperature - °C

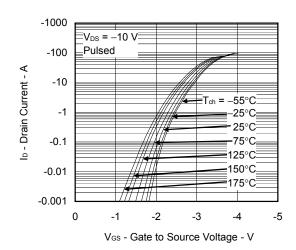
125

175

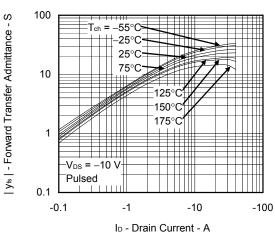
225



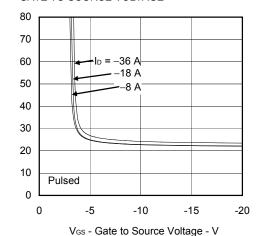
FORWARD TRANSFER CHARACTERISTICS



FORWARD TRANSFER ADMITTANCE vs. DRAIN CURRENT



DRAIN TO SOURCE ON-STATE RESISTANCE vs. GATE TO SOURCE VOLTAGE



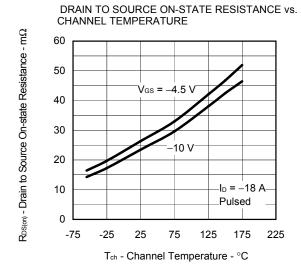
Ves(th) - Gate to Source Threshold Voltage - V

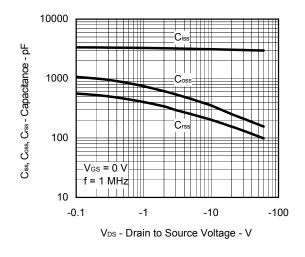
-75

-25

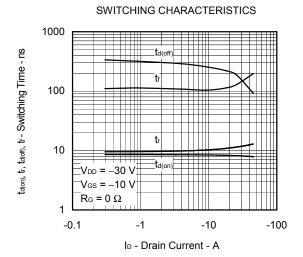
25

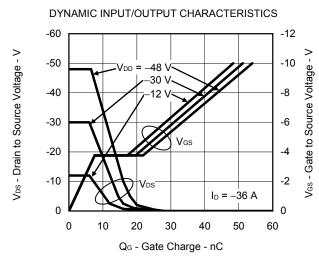
RDS(on) - Drain to Source On-state Resistance - mΩ

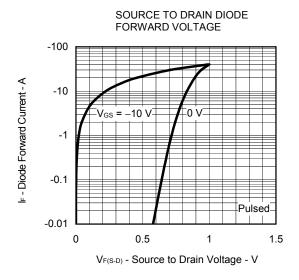


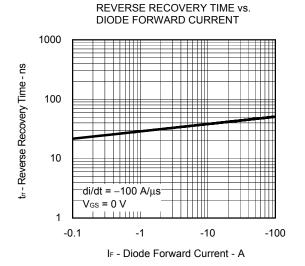


CAPACITANCE vs. DRAIN TO SOURCE VOLTAGE



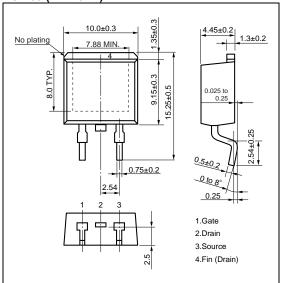




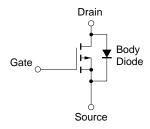


PACKAGE DRAWING (Unit: mm)

TO-263 (MP-25ZK)



EQUIVALENT CIRCUIT



Remark Strong electric field, when exposed to this device, can cause destruction of the gate oxide and ultimately degrade the device operation. Steps must be taken to stop generation of static electricity as much as possible, and quickly dissipate it once, when it has occurred.

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NP36P06KDG

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